

<b>Notice of References Cited</b>	Application/Control No. 10/825,082		Applicant(s)/Patent Under Reexamination FARINA ET AL.	
	Examiner Gunnar J. Gissel		Art Unit 2856	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,579,659 A	12-1996	Roberts, Jeffrey J.	73/168
*	B	US-6,148,815 A	11-2000	Wolf, James L.	128/205.23
*	C	US-6,651,651 B1	11-2003	Bonney et al.	128/200.23
*	D	US-6,665,421 B1	12-2003	Farina, Dino J.	382/100
*	E	US-6,785,400 B1	08-2004	Farina, Dino J.	382/100
*	F	US-6,799,090 B2	09-2004	Farina et al.	700/283
*	G	US-2004/0199296 A1	10-2004	Farina et al.	700/283
*	H	US-2004/0258278 A1	12-2004	Farina, Dino J.	382/100
*	I	US-2005/0016527 A1	01-2005	Barger et al.	128/200.23
*	J	US-2006/0102808 A1	05-2006	Farina et al.	248/074.1
*	K	US-2008/0173067 A1	07-2008	Farina et al.	73/1.16
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	strain gauge. (1992). In Academic Press Dictionary of Science and Technology. Oxford: Elsevier Science & Technology. Retrieved November 17, 2008, from <a href="http://www.credoreference.com/entry/3163700/">http://www.credoreference.com/entry/3163700/</a> .
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.